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Indian Institute of Technology Madras

METHOD AND APPARATUS TO OBTAIN SUB-PITCH PRECISION IN LATERAL MOTION ESTIMATION IN ULTRASOUND ELASTOGRAPHY

IITM Technology Available for Licensing

Problem Statement Technology > Lateral Displacement Estimates (LDE) from ultrasound This method is about estimating the Lateral (side-todata has several benefits like obtaining accurate side) Motion of a Target in Ultrasound Imaging over inverse solutions in elastography, improving shear a specific time interval "t." strain elastogram quality, obtaining good quality A linear transducer array poroelastograms, reliable rotation elastogram etc. "N" elements, separated by distance "λ" > Current methods are reliable only when the imaged Transducer array sends & receives medium is homogeneous, or if the displacement ultrasound beams using "n" active continuity is preserved at the boundaries in the case of transducer elements, where "N"> "n" non-homogeneous medium Technology Category/ Market Category – Biomedical Engineering -Ultrasound Applications techniques,Medical and Surgical, imaging systems, An actuator mechanism inorder to Industry – Biomedical move the transducer array. Market -The global medical imaging market size is expected to grow from \$40.33 billion in 2023 to \$61.51 billion in 2030, at a CAGR of 6.2% in the forecast Involves method that utilizes data from sub-pitch Intellectual Property locations to improve the image quality IITM IDF Ref. 1494 parameters Lateral Motion Estimation of a target in IN201641043467 ultrasound imaging sub-pitch precision is Key Features / Value Proposition obtained at a distance half of the pitch (ie. $\lambda/2$) by translating the sub-aperture by activating odd number Technical Perspective: of consecutive elements and even number of > Improvement in precision of LDE obtained by consecutive elements sequentially. augmenting true RF A-lines at sub-pitch locations compared to interpolating the post-beamformed RF A-No. of positions vs FWHM(mm) line(Fig 1A, B, C) 1.00 -O-· CLA(post) The acquired new frame data that includes pre-0.95 -+- ABT(post) ---- EBT(post) compression and post-compression RF data and is <u> →</u> CLA(pre) -□-ABT(pre) 0.90 FWHM(mm) further processed for image formation that may yield EBT(pre) 0.85 better lateral resolution and lateral displacement estimation (LDE). 0.80 User Perspective: 0.75

- > The sub-pitch precision in lateral displacement estimates improve the quality of shear strain elastograms,poroelastograms,rotation elastograms, LSE etc.
- > Particularly useful in scenarios where targets may move or deform laterally.

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0.70

pitch locations by different methods

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No. of positions

FIG. 1 shows plots of the FWHM obtained in experiments

when using RF Aline data from different number of sub-



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FIG. 2A illustrates the lateral profile at the scatterer location obtained from differentmethods in simulation and FIG. 2B shows a magnified view of a region within the plot

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FIG. 3 illustrates a schematic of the EBT method, where sub-aperture containing consecutive elements totaling to odd and even number of sub-aperture elements are activated to obtain RF A-line data at subpitch locations

- 1. Probe.
- Transducer.
- Linear actuation.
- Transducer elements.
- 5. First acquisition.
- Second acquisition.



Fig.4 Shows schematic of the ABT method used to obtain RFA line data(pre-beam formed or post beamformed) for obtaining sub-pitch resolution

TRL (Technology Readiness Level)

TRL- 4, Technology Validated in the Lab

Research Lab

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